



N-Channel 20-V (D-S) MOSFET

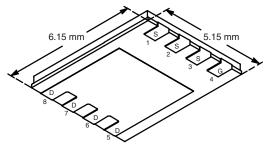
PRODUC	PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)				
20	0.0048 at V _{GS} = 10 V	35	12.7 nC				
20	0.0063 at V _{GS} = 4.5 V	35	12.7 110				

FEATURES

- Halogen-free
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested



PowerPAK® SO-8

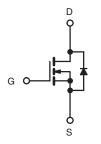


Bottom View

Ordering Information: SiR410DP-T1-GE3 (Lead (Pb)-free and Halogen-free)

APPLICATIONS

- DC/DC Converter
 - Notebook
 - POL



N-Channel MOSFET

Parameter Drain-Source Voltage		Symbol	Limit	Unit	
		V _{DS}	20	V	
Gate-Source Voltage		V_{GS}	± 20	V	
	T _C = 25 °C		35 ^a		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		35 ^a		
Continuous Diain Current (1) = 150 °C)	T _A = 25 °C	I _D	23 ^{b, c}	Α.	
	T _A = 70 °C		18.6 ^{b, c}	A	
Pulsed Drain Current	•	I _{DM}	60		
Avalanche Current	L = 0.1 mH	I _{AS}	35		
Avalanche Energy	L = U.1 IIII	E _{AS}	61	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C		30	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	ls -	3.5 ^{b, c}		
	T _C = 25 °C		36		
Maximum Power Dissipation	T _C = 70 °C	ь	23		
Maximum Fower Dissipation	T _A = 25 °C	P _D	4.2 ^{b, c}	W	
	T _A = 70 °C		2.7 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Tempera		260			

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	25	30	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	2.9	3.5	0/11		

Notes:

- a. Package Limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. See Solder Profile (http://www.vishay.com/ppg?73257). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under Steady State conditions is 70 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-					
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			٧
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A		19		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.3		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.2		2.5	٧
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		V _{DS} = 20 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V, T _J = 55 °C			5	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	40			Α
D : 0	Б	V _{GS} = 10 V, I _D = 20 A		0.004	0.0048	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 19.4 A		0.005	0.0063	Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		70		S
Dynamic ^b				I		
Input Capacitance	C _{iss}			1600		
Output Capacitance	C _{oss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		500		pF
Reverse Transfer Capacitance	C _{rss}			200		
T. 10 . 0		$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		27	41	
Total Gate Charge	Q_g			16.7	25	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 19 \text{ A}$		4.5		
Gate-Drain Charge	Q _{gd}			3.5		
Gate Resistance	R_g	f = 1 MHz		1.3	2.6	Ω
Turn-On Delay Time	t _{d(on)}			25	40	
Rise Time	t _r	V_{DD} = 10 V, R_L = 1 Ω		15	25	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 10 A, V_{GEN} = 4.5 V, R_g = 1 Ω		30	45	1
Fall Time	t _f			15	25	
Turn-On Delay Time	t _{d(on)}			12	20	ns
Rise Time	t _r	V_{DD} = 10 V, R_L = 1 Ω		10	15	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 10$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		25	40	
Fall Time	t _f			10	15	
Drain-Source Body Diode Characteristi	cs			II.		
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			35	۸
Pulse Diode Forward Current	I _{SM}				60	Α
Body Diode Voltage	V_{SD}	I _S = 10 A, V _{GS} = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			30	45	ns
Body Diode Reverse Recovery Charge	Q_{rr}	I _F = 10 A, dI/dt = 100 A/μs, T _{.I} = 25 °C		21	35	nC
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}$, $I_{I} = 100 \text{ A/}\mu\text{S}$, $I_{J} = 25 ^{\circ}\text{C}$		17		
Reverse Recovery Rise Time	t _b			13		ns

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



 $T_C = -55$ °C

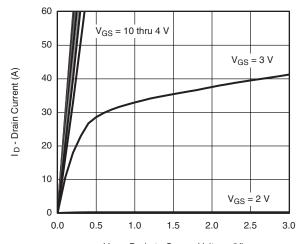
3.0

2.5



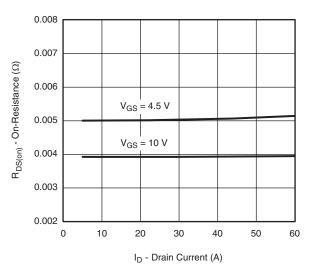


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

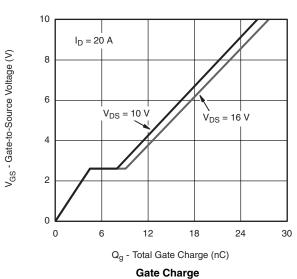


V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics



On-Resistance vs. Drain Current and Gate Voltage



20 16 12 T_C = 25 °C 8 4 T_C = 125 °C 0

ID - Drain Current (A)

0.0

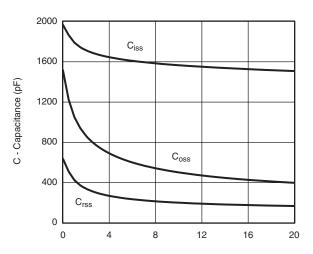
0.5

1.0

1.5 V_{GS} - Gate-to-Source Voltage (V)

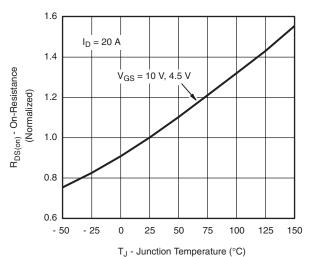
2.0

Transfer Characteristics



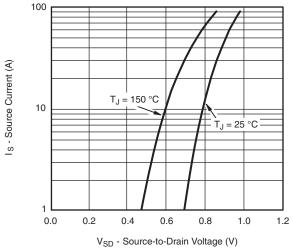
V_{DS} - Drain-to-Source Voltage (V)

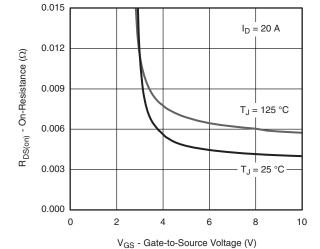
Capacitance



On-Resistance vs. Junction Temperature

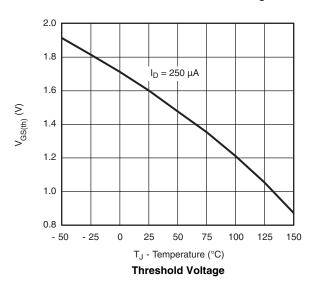
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

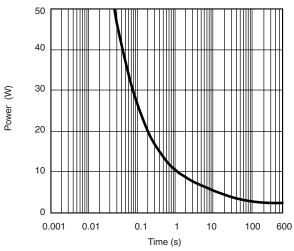




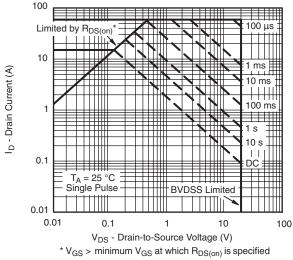
Source-Drain Diode Forward Voltage







Single Pulse Power (Junction-to-Ambient)



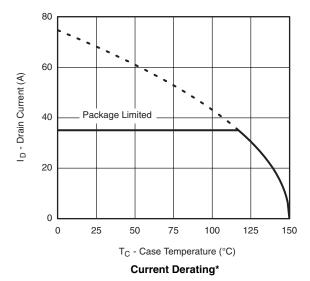
Safe Operating Area, Junction-to-Ambient

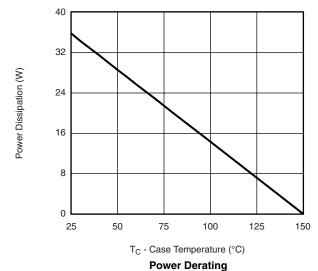






TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

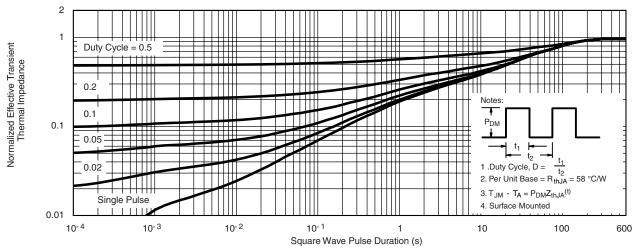




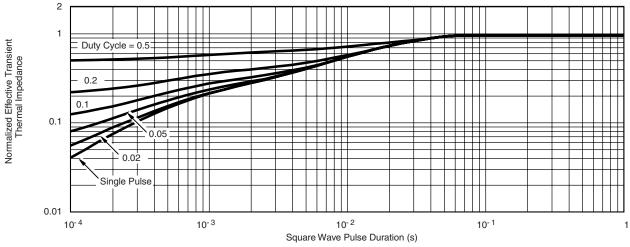
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



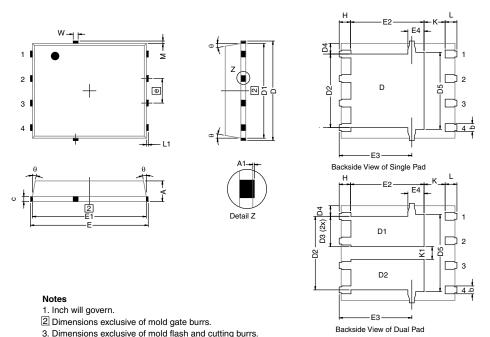
Normalized Thermal Transient Impedance, Junction-to-Case

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?68997.



DWG: 5881

PowerPAK® SO-8, (Single/Dual)



		MILLIMETERS			INCHES	
DIM.	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
Α	0.97	1.04	1.12	0.038	0.041	0.044
A1		-	0.05	0	-	0.002
b	0.33	0.41	0.51	0.013	0.016	0.020
С	0.23	0.28	0.33	0.009	0.011	0.013
D	5.05	5.15	5.26	0.199	0.203	0.207
D1	4.80	4.90	5.00	0.189	0.193	0.197
D2	3.56	3.76	3.91	0.140	0.148	0.154
D3	1.32	1.50	1.68	0.052	0.059	0.066
D4		0.57 typ.			0.0225 typ.	
D5		3.98 typ.			0.157 typ.	
E	6.05	6.15	6.25	0.238	0.242	0.246
E1	5.79	5.89	5.99	0.228	0.232	0.236
E2 (for AL product)	3.30	3.48	3.66	0.130	0.137	0.144
E2 (for other product)	3.48	3.66	3.84	0.137	0.144	0.151
E3	3.68	3.78	3.91	0.145	0.149	0.154
E4 (for AL product)		0.58 typ.			0.023 typ.	
E4 (for other product)		0.75 typ.			0.030 typ.	
е		1.27 BSC			0.050 BSC	
K (for AL product)		1.45 typ.			0.057 typ.	
K (for other product)		1.27 typ.			0.050 typ.	
K1	0.56	-	=	0.022	-	=
Н	0.51	0.61	0.71	0.020	0.024	0.028
L	0.51	0.61	0.71	0.020	0.024	0.028
L1	0.06	0.13	0.20	0.002	0.005	0.008
θ	0°	-	12°	0°	-	12°
W	0.15	0.25	0.36	0.006	0.010	0.014
М		0.125 typ.			0.005 typ.	

Revison: 20-May-13 Document Number: 71655



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Power MOSFETs

Application Note AN821

PowerPAK® SO-8 Mounting and Thermal Considerations

by Wharton McDaniel

MOSFETs for switching applications are now available with die on resistances around 1 m Ω and with the capability to handle 85 A. While these die capabilities represent a major advance over what was available just a few years ago, it is important for power MOSFET packaging technology to keep pace. It should be obvious that degradation of a high performance die by the package is undesirable. PowerPAK is a new package technology that addresses these issues. In this application note, PowerPAK's construction is described. Following this mounting information is presented including land patterns and soldering profiles for maximum reliability. Finally, thermal and electrical performance is discussed.

THE PowerPAK PACKAGE

The PowerPAK package was developed around the SO-8 package (figure 1). The PowerPAK SO-8 utilizes the same footprint and the same pin-outs as the standard SO-8. This allows PowerPAK to be substituted directly for a standard SO-8 package. Being a leadless package, PowerPAK SO-8 utilizes the entire SO-8 footprint, freeing space normally occupied by the leads, and thus allowing it to hold a larger die than a standard SO-8. In fact, this larger die is slightly larger than a full sized DPAK die. The bottom of the die attach pad is exposed for the purpose of providing a direct, low resistance thermal path to the substrate the device is mounted on. Finally, the package height is lower than the standard SO-8, making it an excellent choice for applications with space constraints.



PowerPAK 1212 Devices

Revision: 16-Mai-13

PowerPAK SO-8 SINGLE MOUNTING

The PowerPAK single is simple to use. The pin arrangement (drain, source, gate pins) and the pin dimensions are the same as standard SO-8 devices (see figure 2). Therefore, the PowerPAK connection pads match directly to those of the SO-8. The only difference is the extended drain connection area. To take immediate advantage of the PowerPAK SO-8 single devices, they can be mounted to existing SO-8 land patterns.



Standard SO-8

PowerPAK SO-8

Fig. 2

The minimum land pattern recommended to take full advantage of the PowerPAK thermal performance see Application Note 826, Recommended Minimum Pad Patterns With Outline Drawing Access for Vishay Siliconix MOSFETs. Click on the PowerPAK SO-8 single in the index of this document.

In this figure, the drain land pattern is given to make full contact to the drain pad on the PowerPAK package.

This land pattern can be extended to the left, right, and top of the drawn pattern. This extension will serve to increase the heat dissipation by decreasing the thermal resistance from the foot of the PowerPAK to the PC board and $^{ extstyle >}$ therefore to the ambient. Note that increasing the drain land area beyond a certain point will yield little decrease in foot-to-board and foot-to-ambient thermal resistance. Under specific conditions of board configuration, copper weight and layer stack, experiments have found that >> more than about 0.25 in² to 0.5 in² of additional copper -(in addition to the drain land) will yield little improvement in thermal performance.

Document Number: 7162

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PowerPAK® SO-8 Mounting and Thermal Considerations

PowerPAK SO-8 DUAL

The pin arrangement (drain, source, gate pins) and the pin dimensions of the PowerPAK SO-8 dual are the same as standard SO-8 dual devices. Therefore, the PowerPAK device connection pads match directly to those of the SO-8. As in the single-channel package, the only exception is the extended drain connection area. Manufacturers can likewise take immediate advantage of the PowerPAK SO-8 dual devices by mounting them to existing SO-8 dual land patterns.

To take the advantage of the dual PowerPAK SO-8's thermal performance, the minimum recommended land pattern can be found in Application Note 826, Recommended Minimum Pad Patterns With Outline Drawing Access for Vishay Siliconix MOSFETs. Click on the PowerPAK 1212-8 dual in the index of this document.

The gap between the two drain pads is 24 mils. This matches the spacing of the two drain pads on the PowerPAK SO-8 dual package.

REFLOW SOLDERING

PLICATION

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Vishay Siliconix surface-mount packages meet solder reflow reliability requirements. Devices are subjected to solder reflow as a test preconditioning and are then reliability-tested using temperature cycle, bias humidity, HAST, or pressure pot. The solder reflow temperature profile used, and the temperatures and time duration, are shown in figures 3 and 4.

For the lead (Pb)-free solder profile, see www.vishay.com/doc?73257.



Fig. 3 Solder Reflow Temperature Profile

Ramp-Up Rate	+ 3 °C /s max.
Temperature at 150 - 200 °C	120 s max.
Temperature Above 217 °C	60 - 150 s
Maximum Temperature	255 + 5/- 0 °C
Time at Maximum Temperature	30 s
Ramp-Down Rate	+ 6 °C/s max.



Fig. 4 Solder Reflow Temperatures and Time Durations

www.vishay.com

PowerPAK® SO-8 Mounting and Thermal Considerations

THERMAL PERFORMANCE

Introduction

A basic measure of a device's thermal performance is the junction-to-case thermal resistance, $R_{thJC},$ or the junction-to-foot thermal resistance, R_{thJF} This parameter is measured for the device mounted to an infinite heat sink and is therefore a characterization of the device only, in other words, independent of the properties of the object to which the device is mounted. Table 1 shows a comparison of the DPAK, PowerPAK SO-8, and standard SO-8. The PowerPAK has thermal performance equivalent to the DPAK, while having an order of magnitude better thermal performance over the SO-8.

TABLE 1 - DPAK AND POWERPAK SO-8
EQUIVALENT STEADY STATE
PERFORMANCE

	DPAK	PowerPAK SO-8	Standard SO-8
Thermal Resistance R _{thJC}	1.2 °C/W	1 °C/W	16 °C/W

Thermal Performance on Standard SO-8 Pad Pattern

Because of the common footprint, a PowerPAK SO-8 can be mounted on an existing standard SO-8 pad pattern. The question then arises as to the thermal performance of the PowerPAK device under these conditions. A characterization was made comparing a standard SO-8 and a PowerPAK device on a board with a trough cut out underneath the PowerPAK drain pad. This configuration restricted the heat flow to the SO-8 land pads. The results are shown in figure 5.



PLICATION

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Fig. 5 PowerPAK SO-8 and Standard SO-0 Land Pad Thermal Path

Because of the presence of the trough, this result suggests a minimum performance improvement of 10 °C/W by using a PowerPAK SO-8 in a standard SO-8 PC board mount.

The only concern when mounting a PowerPAK on a standard SO-8 pad pattern is that there should be no traces running between the body of the MOSFET. Where the standard SO-8 body is spaced away from the pc board, allowing traces to run underneath, the PowerPAK sits directly on the pc board.

Thermal Performance - Spreading Copper

Designers may add additional copper, spreading copper, to the drain pad to aid in conducting heat from a device. It is helpful to have some information about the thermal performance for a given area of spreading copper.

Figure 6 shows the thermal resistance of a PowerPAK SO-8 device mounted on a 2-in. 2-in., four-layer FR-4 PC board. The two internal layers and the backside layer are solid copper. The internal layers were chosen as solid copper to model the large power and ground planes common in many applications. The top layer was cut back to a smaller area and at each step junction-to-ambient thermal resistance measurements were taken. The results indicate that an area above 0.3 to 0.4 square inches of spreading copper gives no thermal performance improvement. subsequent experiment was run where the copper on the back-side was reduced, first to 50 % in stripes to mimic circuit traces, and then totally removed. No significant effect was observed.



Fig. 6 Spreading Copper Junction-to-Ambient Performance

Document Number: 71622

PowerPAK® SO-8 Mounting and Thermal Considerations

SYSTEM AND ELECTRICAL IMPACT OF PowerPAK SO-8

In any design, one must take into account the change in MOSFET R_{DS(on)} with temperature (figure 7).



Fig. 7 MOSFET R_{DS(on)} vs. Temperature

A MOSFET generates internal heat due to the current passing through the channel. This self-heating raises the junction temperature of the device above that of the PC board to which it is mounted, causing increased power dissipation in the device. A major source of this problem lies in the large values of the junction-to-foot thermal resistance of the SO-8 package.

PowerPAK SO-8 minimizes the junction-to-board thermal resistance to where the MOSFET die temperature is verv close to the temperature of the PC board. Consider two devices mounted on a PC board heated to 105 °C by other components on the board (figure 8).

Suppose each device is dissipating 2.7 W. Using the junction-to-foot thermal resistance characteristics of the PowerPAK SO-8 and the standard SO-8, the die temperature is determined to be 107 °C for the PowerPAK (and for DPAK) and 148 °C for the standard SO-8. This is a 2 °C rise above the board temperature for the PowerPAK and a 43 °C rise for the standard SO-8. Referring to figure 7, a 2 °C difference has minimal effect on R_{DS(on)} whereas a 43 °C difference has a significant effect on R_{DS(on)}.

Minimizing the thermal rise above the board temperature by using PowerPAK has not only eased the thermal design but it has allowed the device to run cooler, keep $r_{\text{DS(on)}}\,\text{low},$ and permits the device to handle more current than the same MOSFET die in the standard SO-8 package.

CONCLUSIONS

PowerPAK SO-8 has been shown to have the same thermal performance as the DPAK package while having the same footprint as the standard SO-8 package. The PowerPAK SO-8 can hold larger die approximately equal in size to the maximum that the DPAK can accommodate implying no sacrifice in performance because of package limitations.

Recommended PowerPAK SO-8 land patterns are provided to aid in PC board layout for designs using this new package.

Thermal considerations have indicated that significant advantages can be gained by using PowerPAK SO-8 devices in designs where the PC board was laid out for the standard SO-8. Applications experimental data gave thermal performance data showing minimum and typical thermal performance in a SO-8 environment, plus information on the optimum thermal performance obtainable including spreading copper. This further emphasized the DPAK equivalency.

PowerPAK SO-8 therefore has the desired small size characteristics of the SO-8 combined with the attractive thermal characteristics of the DPAK package.



Fig. 8 Temperature of Devices on a PC Board

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RECOMMENDED MINIMUM PADS FOR PowerPAK® SO-8 Single



Recommended Minimum Pads Dimensions in Inches/(mm)

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APPLICATION NOTE



Useful Web Links

COMPARE MOSFET PACKAGES

www.vishay.com/mosfets/tapereel-package-list/

FEATURED MOSFET FAMILIES

www.vishav.com/landingpage/tradeshows/powermanagement/2011/mosfets.html

CHECK DISTRIBUTOR STOCK

www.vishay.com/search?query=&type=inv&search-inventory-submit.x=41&search-inventory-submit.v=13

SAMPLES

www.vishay.com/how/samples/

SALES CONTACTS

www.vishay.com/company/contacts/

PCNS (if applicable)

www.vishay.com/how/pcn/ www.vishay.com/qualitv/pcn-search/

APPLICATION NOTES

www.vishay.com/mosfets/related/#appnot

ON-LINE LITERATURE

www.vishay.com/how/onlineliterature/online-libraries/

THERMAL SIMULATION

www.vishay.com/mosfets/thermasim/

See Application Note AN832 (www.vishay.com/doc?69510) for the ThermaSim User Guide.

RELIABILITY INFORMATION

www.vishay.com/doc?70863

SPICE MODELS

Available spice models are located on the specific device's web product page. See Application Note AN838 (www.vishay.com/doc?65038) for tips downloading, preparing and using them.



Devices:

PowerPAK® SO-8, PowerPAK SO-8L PowerPAK 1212-8, PowerPAK 1212-8S, PowerPAK 1212-8W PowerPAIR® 6 x 3.7, PowerPAIR 6 x 5, PowerPAIR 3 x 3

Single and Dual



7401 = Example Base Part Number or marking code a

= Siliconix Logo

LL = Lot Code

= ESD Symbol

= Pin 1 Indicator

T = Assembly Factory Code

Y = Year Code

W = Week Code

F = Wafer Fab Code

The current marking strategy is reflected. Contact your local sales representative for historical marking strategies for these packages.

Note

 These digits will be a code, if indicated on the datasheet. Otherwise, the digits will be the base number like indicated in the example.

ENVIRONMENTAL AND PACKAGE TESTING DATA FOR PowerPAK® SO-8 SOLDER PROCESS								
STRESS	SAMPLE SIZE	DEVICE HR./CYC	CONDITION	TOTAL FAILS	FAIL PERCENTAGE			
BOND INT	400	200 000	200 °C + N2	0	0			
HAST	2956	295 600	130 °C, 85 % RH	0	0			
Pressure Pot	3332	319 872	121°, 15 PSIG	0	0			
Solder DUNK	1217	3651	260 °C, 10 s	0	0			
Solderability	165	1320	883 M2003	0	0			
Temp. Cycle	5500	2 625 300	-55 °C to 150 °C	0	0			



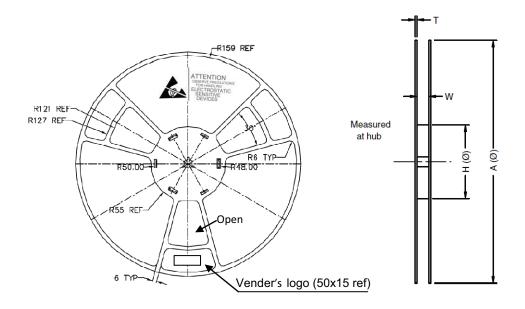
N-CHANNEL ACCELERATED OPERATING LIFE TEST RESULT				
Sample Size 232 395				
Equivalent Device Hours	28 904 254 900			
Failure Rate in FIT	1.073			

Failure Rate in FIT is calculated according to JEDEC Standard JESD85, *Methods for Calculating Failure Rates in Units of FITs*, based on accelerated high temperature operating life test results by using an apparent activation energy of 0.7 eV. The junction temperature of the device at use is assumed to be 55 °C. A constant failure rate distribution is assumed. The upper confidence bound of the failure rate is 60 %.



Reel

330 mm Reel (Lock Reel)



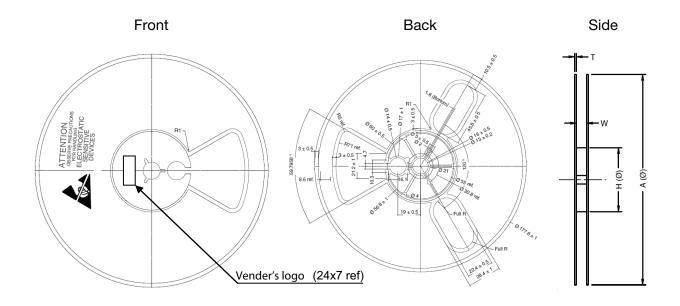
Note:

- 1. Material: Antistatic or conductor plastic
- 2. All dimensions in mm
- 3. ESD-surface resistivity- 10^4 to $10^{11} \Omega/sq$
- 4. Color: Black

VER	APPLICA	TION	Α	W	TAPE WIDTH	Н	T
- 1	SOIC-14/16 TO-251 (Short Lead) TO-252/TO-252 (Reverse Lead) PLCC-20 TSSOP-8/14/16/20/28 SSOP-24 SOIC-16 (W)	PowerPAK MLF 9 x 9 PowerPAK MLP 6 x 6 MLF 8 x 8 PowerPAK 8 x 8L PowerPAK 8 x 8 MLP77	330 ± 2	16.4 ^{+2.0} ₋₀	16	100 ± 1	2.5 ± 0.5
-2	SOIC-8 (N), SOIC-8 (N) epad MSOP-8/10 PowerPAK® SO-8 PowerPAK 1212 PowerPAK 1212-8W MICRO FOOT® MLP33-5, MLP33-8, MLP33-10 QFN (4 x 4)/(3 x 3)/DFN-10 (3 x 3)/ MLP44-16L MLP65-18/20L	PolarPAK® MLP55 PowerPAIR® 6 x 5 PowerPAIR 6 x 3 J PowerPAIR SO-8L PolarPAK1215 PowerPAIR 6 x 3.7 PowerPAK SO-8L MLP4.5 x 3.5-22L	330 ± 2	12.4 +2.0 -0	12	100 ± 1	2.5 ± 0.5
- 4	SOT-23/143 SC70 MICRO FOOT	TSOP-6, 1206-8 ChipFET PowerPAK SC70, PowerPAK SC75	330 ± 2	8.4 +1.5 -0	8.4	100 ± 1	2.5 ± 0.5
- 5	SOIC-20W/24W D ² PAK SSOP-28 QSOP-36	PowerPAK MLF 10 x 10	330 ± 2	24.4 +2.0 -0	24	100 ± 1	2.5 ± 0.5
- 8	KGD		330 ± 2	16.4 ^{+2.0} ₋₀	16	130 ± 1	2.5 ± 0.5

Revision: 15-Jun-15 1 Document Number: 71385

178 mm Reel (Complete Reel)



Note:

- 1. Material: Antistatic or conductor plastic
- 2. All dimensions in mm
- 3. ESD-surface resistivity- 10^4 to $10^{11} \Omega/sq$
- 4. Color: Black

VER	APPL	ICATION	Α	W	TAPE WIDTH	Н	Т
- 3	SOT-23/143 TSOP-5/6/SC70JW-8L 1206-8 ChipFET® SC70/SC75A/SC89 MICRO FOOT SC-89 (SOT-666) SOT23-5, 6 KGD WCSP PowerPAK 0806	PowerPAK SC70 PowerPAK SC75 MiniQFN PowerPAK MLP22-5 PowerPAK ChipFET PowerPAK SC75-6L (PIC) PowerPAK TSC75-6L (PIC) TDFN4 1.2 x 1.6, TDFN8 2 x 2 Thin PowerPAK SC-70 Thin PowerPAK SC-75	178 ± 2	8.4 ^{+1.5} ₋₀	8.4	62 ± 2	1.5 ± 0.5
- 7	MICRO FOOT PowerPAK 2 x 5	KGD	178 ± 2	12.4 +2.0 -0	12	55 ± 2	1.6 ± 0.25

ECN: C15-0680-Rev. BR, 15-Jun-15

DWG: 93-5211-X



N-Channel 20 V (D-S) MOSFET

DESCRIPTION

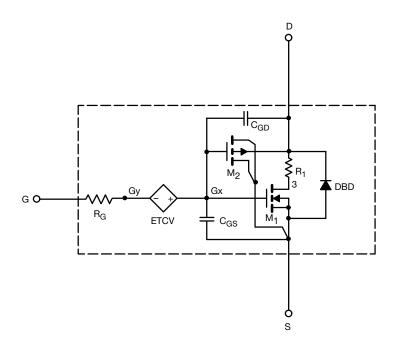
The attached SPICE model describes the typical electrical characteristics of the n-channel vertical DMOS. The subcircuit model is extracted and optimized over the - $55\,^{\circ}$ C to 125 $^{\circ}$ C temperature ranges under the pulsed 0 V to 10 V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

CHARACTERISTICS

- N-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the 55 °C to + 125 °C Temperature Range
- · Model the Gate Charge

SUBCIRCUIT MODEL SCHEMATIC



Note

• This document is intended as a SPICE modeling guideline and does not constitute a commercial product datasheet. Designers should refer to the appropriate datasheet of the same number for guaranteed specification limits.



SPICE Device Model SiR410DP

Vishay Siliconix

SPECIFICATIONS (T _J = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	SIMULATED DATA	MEASURED DATA	UNIT	
Static						
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.5	-	V	
Drain-Source On-State Resistance ^a	D	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	0.004	0.004	Ω	
	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 19.4 \text{ A}$	0.005	0.005		
Forward Transconductancea	9fs	$V_{DS} = 15 \text{ V}, I_{D} = 20 \text{ A}$	80	70	S	
Diode Forward Voltage	V _{SD}	I _S = 10 A	0.79	0.80	V	
Dynamic ^b						
Input Capacitance	C _{iss}		1560	1600		
Output Capacitance	C _{oss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	503	500	pF	
Reverse Transfer Capacitance	C _{rss}		200	200		
Total Gate Charge	Qg	$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	25	27		
			13	16.7	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$	4.5	4.5	110	
Gate-Drain Charge	Q _{gd}		3.5	3.5		

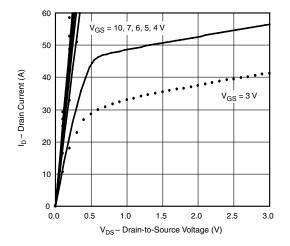
Notes

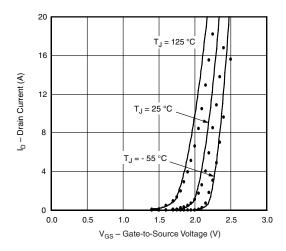
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

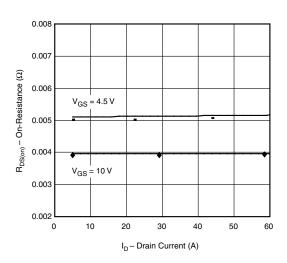
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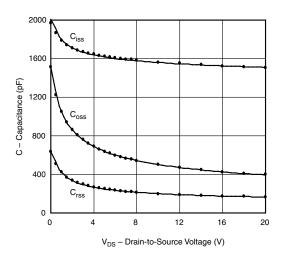
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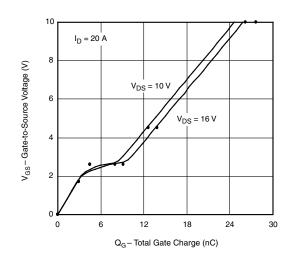
COMPARISON OF MODEL WITH MEASURED DATA ($T_J = 25$ °C, unless otherwise noted)

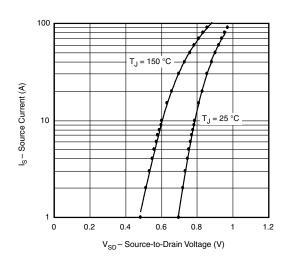












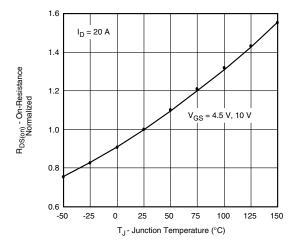
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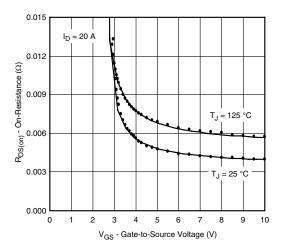
• Dots and squares represent measured data.

SPICE Device Model SiR410DP

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COMPARISON OF MODEL WITH MEASURED DATA ($T_J = 25$ °C, unless otherwise noted)





Note

• Dots and squares represent measured data.



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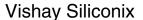
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Revision: 02-Oct-12 Document Number: 91000





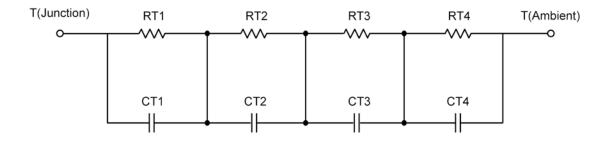
R-C Thermal Model Parameters

DESCRIPTION

The parametric values in the R-C thermal model have been derived using curve-fitting techniques. R-C values for the electrical circuit in the Foster/Tank and Cauer/Filter configurations are included. When implemented in P-Spice, these values have matching characteristic curves to the single-pulse transient thermal impedance curves for the MOSFET.

These RC values can be used in the P-SPICE simulation to evaluate the thermal behavior of the MOSFET junction temperature under a defined power profile. These techniques are described in Application Note AN609, "Thermal Simulation of Power MOSFETs on the P-Spice Platform."

R-C THERMAL MODEL FOR TANK CONFIGURATION



C VALUES FOR TAN	VALUES FOR TANK CONFIGURATION				
Thermal Resistance (°C/W)					
Junction to	Ambient	Case	Foot		
RT1	1.9921	546.0005 m	N/A		
RT2	12.7242	284.8987 m	N/A		
RT3	10.4306	492.2008 m	N/A		
RT4	44.8531	2.1769	N/A		
	Thermal Capacit	ance (Joules/°C)			
Junction to	Ambient	Case	Foot		
CT1	1.4947 m	600.9468 u	N/A		
CT2	506.3593 m	30.2059 m	N/A		
CT3	38.2285 m	9.4434 m	N/A		
CT4	1.6532	9.4063 m	N/A		

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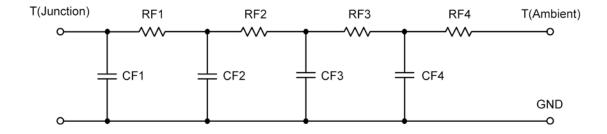
Document Number: 69038

Revision: 27-Oct-08

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1



R-C THERMAL MODEL FOR FILTER CONFIGURATION



Thermal Resistance (°C/W)				
Junction to	Ambient	Case	Foot	
RF1	2.2098	956.0920 m	N/A	
RF2	13.0792	1.3571	N/A	
RF3	21.1865	649.5091 m	N/A	
RF4	33.5245	537.2989 m	N/A	
	Thermal Capacit	tance (Joules/°C)		
Junction to	Ambient	Case	Foot	
CF1	1.7629 m	737.3986 u	N/A	
CF2	35.3857 m	5.4126 m	N/A	
CF3	458.6534 m	2.7800 m	N/A	
CF4	1.6882	1.1187 m	N/A	

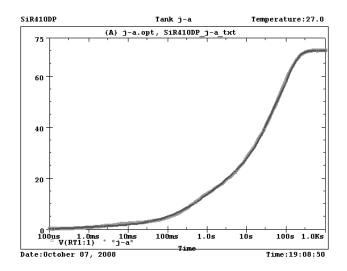
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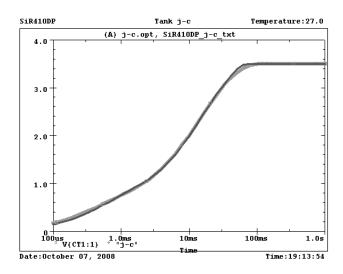
NA indicates not applicable

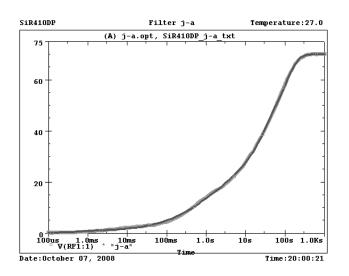
Document Number: 69038 Revision: 27-Oct-08

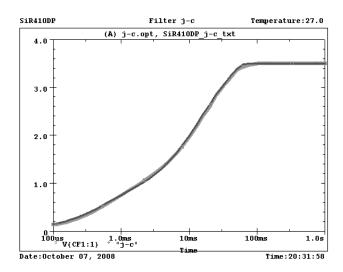






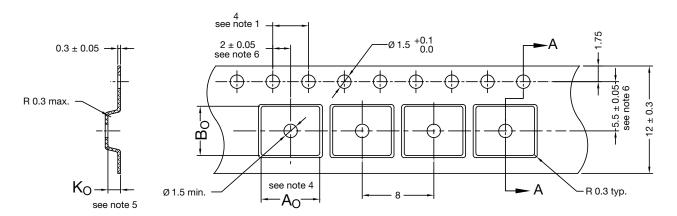








PowerPAK® SOIC-8



Section A-A

 $A_0 = 6.5 \text{ mm} \pm 0.1 \text{ mm}$

 $B_0 = 5.5 \text{ mm} \pm 0.1 \text{ mm}$

 $K_0 = 1.4 \text{ mm} \pm 0.1 \text{ mm}$

Notes

- $^{(1)}$ 10 sprocket hole pitch cumulative tolerance \pm 0.2 mm.
- (2) Camber not to exceed 1 mm in 100 mm, also not to exceed 1.5 cm in 1 m actually.
- (3) Material: Black conductive or black static dissipative.
- (4) For advantek carrier tape, AO and BO are calculate on a plane at a distance "R" above the bottom of the pocket.
- (5) K_O measured from a plane on the inside bottom of the pocket to the top surface of the carrier.
- (6) It should be measured from:
 - a. sprocket hole to pocket center
 - b. sprocket hole to pocket hole
- (7) All sizes in mm unless specified.
- $^{(8)}$ Tolerances will be \pm 0.1 mm unless specified.
- (9) Vishay part number must be labeled at all reels of carrier tape.
- (10) Surface resistivity: 10^4 to 10^{11} Ω .

QUANTITY PER REEL			
T1	3000		

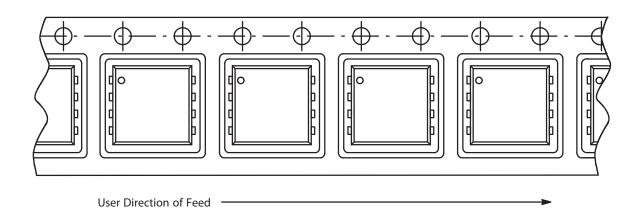
ECN: C15-0525-Rev. F, 08-Jun-15

DWG: 90-2378-1



Device Orientation PowerPAK® 1212-8, PowerPAK 1212-8S, PowerPAK 1212-8W PowerPAK SO-8

DEVICE ORIENTATION		
PACKAGE	METHOD	
PowerPAK 1212-8	T1	
PowerPAK 1212-8S	T1	
PowerPAK 1212-8W	T1	
PowerPAK SO-8	T1	



Revision control of this drawing is maintained through Document Control, Pack Specification-PACK-0007-14



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